

From First STM to Essential Systems for Research and Education in Nano Technology Area.

Over the last three decades, Scanning Probe Microscopy has been evolving from the very first Scanning Tunneling Microscope developed by Dr. Gerd Binnig and Dr. Heinrich Rohrer in 1981, to complex Atomic Force Microscopes (AFM) and systems based on AFM techniques. From topography to electrical properties at nano scales, from quantitative nano-mechanical information to chemical compositions at scales below the diffraction limit – AFM has proven to be a sustainable technique with infinite capabilities. In this talk we present the latest AFM developments and applications for Research and Education in Nano Technology Area.